

Notice of References Cited	Application/Control No. 10/559,497		Applicant(s)/Patent Under Reexamination FUJII, TAKEHIRO	
	Examiner MORGAN VARNER		Art Unit 2895	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0190770	10-2003	Yeom et al.	438/113
*	B	US-2004/0056260	03-2004	Slater et al.	257/079
*	C	US-2002/0123164	09-2002	Slater et al.	438/39
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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